

## MicroConverter™, Multichannel 12-Bit ADC with Embedded FLASH MCU

ADuC812

#### **FEATURES**

#### **ANALOG I/O**

8-Channel, High Accuracy 12-Bit ADC On-Chip, 40 ppm/°C Voltage Reference High Speed 200 kSPS

DMA Controller for High Speed ADC-to-RAM Capture

Two 12-Bit Voltage Output DACs

**On-Chip Temperature Sensor Function** 

#### **MEMORY**

8K Bytes On-Chip Flash/EE Program Memory 640 Bytes On-Chip Flash/EE Data Memory

On-Chip Charge Pump (No Ext. V<sub>PP</sub> Requirements)

256 Bytes On-Chip Data RAM

16M Bytes External Data Address Space

64K Bytes External Program Address Space

#### 8051-COMPATIBLE CORE

12 MHz Nominal Operation (16 MHz Max)

Three 16-Bit Timer/Counters

32 Programmable I/O lines

**High Current Drive Capability—Port 3** 

Nine Interrupt Sources, Two Priority Levels

Specified for 3 V and 5 V Operation Normal, Idle and Power-Down Modes

#### **ON-CHIP PERIPHERALS**

**UART Serial I/O** 

2-Wire (I<sup>2</sup>C®-Compatible) and SPI® Serial I/O

Watchdog Timer

**Power Supply Monitor** 

#### **APPLICATIONS**

Intelligent Sensors (IEEE 1451.2-Compatible) Battery Powered Systems (Portable PCs, Instruments,

Monitors)

**Transient Capture Systems** 

**DAS and Communications Systems** 

#### **GENERAL DESCRIPTION**

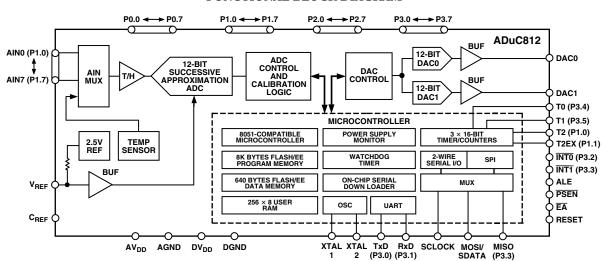
The ADuC812 is a fully integrated 12-bit data acquisition system incorporating a high performance self-calibrating multichannel ADC, two 12-bit DACs and programmable 8-bit (8051-compatible) MCU on a single chip.

The programmable 8051-compatible core is supported by 8K bytes Flash/EE program memory, 640 bytes Flash/EE data memory and 256 bytes data SRAM on-chip.

Additional MCU support functions include Watchdog Timer, Power Supply Monitor and ADC DMA functions. 32 Programmable I/O lines, I<sup>2</sup>C-compatible, SPI and Standard UART Serial Port I/O are provided for multiprocessor interfaces and I/O expansion.

Normal, idle and power-down operating modes for both the MCU core and analog converters allow for flexible power management schemes suited to low power applications. The part is specified for 3 V and 5 V operation over the industrial temperature range and is available in a 52-lead, plastic quad flatpack package.

#### FUNCTIONAL BLOCK DIAGRAM



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 $\begin{array}{l} \textbf{ADUC812-SPECIFICATIONS}^{1,\;2}(\text{AV}_{\text{DD}} = \text{DV}_{\text{DD}} = +3.0 \text{ V or } +5.0 \text{ V} \pm 10\%, \text{V}_{\text{REF}} = 2.5 \text{ V Internal Reference,} \\ \text{MCLKIN} = 16.0 \text{ MHz, DAC V}_{\text{OUT}} \text{ Load to AGND; R}_{\text{L}} = 10 \text{ k}\Omega, \text{ C}_{\text{L}} = 100 \text{ pF. All specifications T}_{\text{A}} = \text{T}_{\text{MIN}} \text{ to T}_{\text{MAX}}, \text{ unless otherwise noted.}) \end{array}$ 

	ADu	C812BS		Test Conditions/Comments	
Parameter	$V_{DD} = 5 V$	$V_{DD} = 3 V$	Units		
ADC CHANNEL SPECIFICATIONS					
DC ACCURACY <sup>3, 4</sup>					
Resolution	12	12	Bits		
Integral Nonlinearity	±1/2	$\pm 1/2$	LSB typ	$f_{SAMPLE} = 100 \text{ kHz}$	
,	±1.5		LSB max	$f_{SAMPLE} = 100 \text{ kHz}$	
	±1.5	±1.5	LSB typ	$f_{\text{SAMPLE}} = 200 \text{ kHz}$	
Differential Nonlinearity	±1	±1	LSB typ	$f_{\text{SAMPLE}} = 100 \text{ kHz}$ . Guaranteed No	
				Missing Codes at 5 V	
CALIBRATED ENDPOINT ERRORS $^{5,  6}$					
Offset Error	±5		LSB max		
	±1	$\pm 2$	LSB typ		
Offset Error Match	1	1	LSB typ		
Gain Error	±6		LSB max		
	±1	$\pm 2$	LSB typ		
Gain Error Match	1.5	1.5	LSB typ		
USER SYSTEM CALIBRATION <sup>7</sup>					
Offset Calibration Range	±5	±5	% of V <sub>REF</sub> typ		
Gain Calibration Range	±2.5	±2.5	% of V <sub>REF</sub> typ		
DYNAMIC PERFORMANCE				f <sub>IN</sub> = 10 kHz Sine Wave	
			15	$f_{SAMPLE} = 100 \text{ kHz}$	
Signal-to-Noise Ratio (SNR) <sup>8</sup>	70	70	dB typ		
Total Harmonic Distortion (THD)	<b>−78</b>	-78	dB typ		
Peak Harmonic or Spurious Noise	-78	-78	dB typ		
ANALOG INPUT					
Input Voltage Ranges	0 to V <sub>REF</sub>	$0$ to $V_{REF}$	Volts		
Leakage Current	±10		μA max		
	±1	+1	μA typ		
Input Capacitance	20	20	pF max		
TEMPERATURE SENSOR <sup>9</sup>					
Voltage Output at +25°C	600	600	mV typ	Measured On-Chip via a Typical	
Voltage TC	-3.0	-3.0	mV/°C typ	±0.5 LSB (610 μV) Accurate ADC	
DAC CHANNEL SPECIFICATIONS					
DC ACCURACY <sup>10</sup>					
Resolution	12	12	Bits		
Relative Accuracy	±3	±3	LSB typ		
Differential Nonlinearity	±0.5	±1	LSB typ	Guaranteed 12-Bit Monotonic	
Offset Error	±50		mV max		
	±25	±25	mV typ		
Full-Scale Error	±25		mV max		
	±10	$\pm 10$	mV typ		
Full-Scale Mismatch	±0.5	±0.5	% typ	% of Full-Scale on DAC1	
ANALOG OUTPUTS					
Voltage Range_0	0 to V <sub>REF</sub>	$0$ to $V_{REF}$	V typ		
Voltage Range_1	0 to V <sub>DD</sub>	$0$ to $V_{\mathrm{DD}}$	V typ		
Resistive Load	10	10	kΩ typ		
Capacitive Load	100	100	pF typ		
Output Impedance	0.5	0.5	Ω typ		
$I_{SINK}$	50	50	μA typ		

	ADu	C812BS			
Parameter	$V_{DD} = 5 V$	$V_{DD} = 3 V$	Units	Test Conditions/Comments	
DAC AC CHARACTERISTICS					
Voltage Output Settling Time	15	15	μs typ	Full-Scale Settling Time to Within 1/2 LSB of Final Value	
Digital-to-Analog Glitch Energy	10	10	nV sec typ	1 LSB Change at Major Carry	
REFERENCE INPUT/OUTPUT					
REF <sub>IN</sub> Input Voltage Range	$2.3/V_{ m DD}$	$2.3/V_{ m DD}$	V min/max		
Input Impedance	150	150	kΩ typ		
REF <sub>OUT</sub> Output Voltage	2.45/2.55		V min/max		
	2.5	2.5	V typ		
REF <sub>OUT</sub> Tempco	40	40	ppm/°C typ		
FLASH/EE MEMORY PERFORMANCE CHARACTERISTICS <sup>11, 12</sup>					
Endurance	10,000		Cycles min		
	50,000	50,000	Cycles typ		
Data Retention	10	•	Years min		
WATCHDOG TIMER					
CHARACTERISTICS					
Oscillator Frequency	64	64	kHz typ		
POWER SUPPLY MONITOR					
CHARACTERISTICS					
Power Supply Trip Point Accuracy	±2.5		% of Selected		
			Nominal Trip		
			Point Voltage		
			max		
	±1.0	$\pm 1.0$	% of Selected		
			Nominal Trip		
			Point Voltage		
			typ		
DIGITAL INPUTS					
Input High Voltage (V <sub>INH</sub> )	2.4		V min		
Input Low Voltage (V <sub>INI</sub> )	0.8		V max		
Input Leakage Current (Port 0, $\overline{EA}$ )	±10		uA max	$V_{IN} = 0 \text{ V or } V_{DD}$	
input Boundge Guirent (1 oft 0, 121)	±1	±1	μA typ	$V_{IN} = 0 \text{ V or } V_{DD}$	
Logic 1 Input Current		± 1	μιτγρ	VIN O V OI VDD	
(All Digital Inputs)	±10		μA max	$V_{IN} = V_{DD}$	
(	±1	±1	μA typ	$V_{\rm IN} = V_{\rm DD}$	
Logic 0 Input Current (Port 1, 2, 3)	<del>-80</del>		μA max	עעי אוי	
(1 off 1, 2, 3)	-40	-40	μΑ typ	$V_{II} = 450 \text{ mV}$	
I - i - 1 0 Transition Comment (Boot 1 0 2)	- <del>7</del> 00	10	μA max	$V_{\rm IL} = 450 \mathrm{mV}$ $V_{\rm IL} = 2 \mathrm{V}$	
LOGIC I-U Transition Chreen (Port 1 / 5)					
Logic 1-0 Transition Current (Port 1, 2, 3)	-400	-400	μA typ	$V_{IL} = 2 \text{ V}$	

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## ADuC812—SPECIFICATIONS<sup>1, 2</sup>

	ADu	C812BS			
Parameter	$V_{DD} = 5 V$	$V_{DD} = 3 V$	Units	Test Conditions/Comments	
DIGITAL OUTPUTS					
Output High Voltage (V <sub>OH</sub> )	2.4		V min	$V_{DD} = 4.5 \text{ V}$ to 5.5 V	
				$I_{SOURCE} = 80 \mu A$	
	4.0	2.6	V typ	$V_{DD} = 2.7 \text{ V to } 3.3 \text{ V}$	
				$I_{SOURCE} = 20 \mu A$	
Output Low Voltage (VOL)					
ALE, $\overline{\text{PSEN}}$ , Ports 0 and 2	0.4		V max	$I_{SINK} = 1.6 \text{ mA}$	
	0.2	0.2	V typ	$I_{SINK} = 1.6 \text{ mA}$	
Port 3	0.4		V max	$I_{SINK} = 8 \text{ mA}$	
	0.2	0.2	V typ	$I_{SINK} = 8 \text{ mA}$	
Floating State Leakage Current	±10		μA max		
	±5	±5	μA typ		
Floating State Output Capacitance	10	10	pF typ		
POWER REQUIREMENTS <sup>13, 14, 15</sup>					
I <sub>DD</sub> Normal Mode <sup>16</sup>	42		mA max	MCLKIN = 16 MHz	
	32	16	mA typ	MCLKIN = 16 MHz	
	26	12	mA typ	MCLKIN = 12 MHz	
	8	3	mA typ	MCLKIN = 1 MHz	
I <sub>DD</sub> Idle Mode	25		mA max	MCLKIN = 16 MHz	
	18	17	mA typ	MCLKIN = 16 MHz	
	15	6	mA typ	MCLKIN = 12 MHz	
	7	2	mA typ	MCLKIN = 1 MHz	
I <sub>DD</sub> Power-Down Mode <sup>17</sup>	50	50	μA max		
	5	5	μA typ		

#### NOTES

Specifications subject to change without notice.

Please refer to User Guide, Quick Reference Guide, Application Notes and Silicon Errata Sheet at www.analog.com/microconverter for additional information.

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<sup>&</sup>lt;sup>1</sup>Specifications apply after calibration.

<sup>&</sup>lt;sup>2</sup>Temperature range -40°C to +85°C.

<sup>&</sup>lt;sup>3</sup>Linearity is guaranteed during normal MicroConverter Core operation.

<sup>&</sup>lt;sup>4</sup>Linearity may degrade when programming or erasing the 640 Byte Flash/EE space during ADC conversion times due to on-chip charge pump activity.

 $<sup>^5</sup>$ Measured in production at  $V_{\rm DD}$  = 5 V after Software Calibration Routine at +25°C only.

<sup>&</sup>lt;sup>6</sup>User may need to execute Software Calibration Routine to achieve these specifications, which are configuration dependent.

<sup>&</sup>lt;sup>7</sup>The offset and gain calibration spans are defined as the voltage range of user system offset and gain errors that the ADuC812 can compensate.

<sup>&</sup>lt;sup>8</sup>SNR calculation includes distortion and noise components.

<sup>&</sup>lt;sup>9</sup>The temperature sensor will give a measure of the die temperature directly, air temperature can be inferred from this result.

<sup>&</sup>lt;sup>10</sup>DAC linearity is calculated using:

reduced code range of 48 to 4095, 0 to V<sub>REF</sub> range

reduced code range of 48 to 3995, 0 to  $V_{\rm DD}$  range

DAC output load =  $10 \text{ k}\Omega$  and 50 pF.

<sup>11</sup>Flash/EE Memory Performance Specifications are qualified as per JEDEC Specification A103 (Data Retention) and JEDEC Draft Specification All7 (Endurance).

<sup>&</sup>lt;sup>12</sup>Endurance Cycling is evaluated under the following conditions:

Mode = Byte Programming, Page Erase Cycling

Cycle Pattern = 00Hex to FFHex

Erase Time = 20 msProgram Time =  $100 \mu \text{s}$ 

<sup>&</sup>lt;sup>13</sup>I<sub>DD</sub> at other MCLKIN frequencies is typically given by:

 $<sup>\</sup>begin{array}{lll} & \text{Top at other MCLKIN requestes is typically given by.} \\ & \text{Normal Mode (V}_{\text{DD}} = 5 \text{ V}): & \text{I}_{\text{DD}} = (1.6 \times \text{MCLKIN}) + 6 \\ & \text{Normal Mode (V}_{\text{DD}} = 3 \text{ V}): & \text{I}_{\text{DD}} = (0.8 \times \text{MCLKIN}) + 3 \\ & \text{Idle Mode (V}_{\text{DD}} = 5 \text{ V}): & \text{I}_{\text{DD}} = (0.75 \times \text{MCLKIN}) + 6 \\ & \text{Idle Mode (V}_{\text{DD}} = 3 \text{ V}): & \text{I}_{\text{DD}} = (0.25 \times \text{MCLKIN}) + 3 \\ \end{array}$ 

Where MCLKIN is the oscillator frequency in MHz and resultant  $I_{\rm DD}$  values are in mA.

 $<sup>^{14}\</sup>mathrm{I}_\mathrm{DD}$  Currents are expressed as a summation of analog and digital power supply currents during normal MicroConverter operation.

 $<sup>^{15}</sup>I_{DD}$  is not measured during Flash/EE program or erase cycles;  $I_{DD}$  will typically increase by 10 mA during these cycles.

 $I_{\rm DD}$  = 2 mA (typ) in normal operation (internal  $V_{\rm REF}$ , ADC and DAC peripherals powered on).

 $<sup>^{17}\</sup>text{EA} = \text{Port0} = \text{DV}_{\text{DD}}$ , XTAL1 (Input) tied to  $\text{DV}_{\text{DD}}$ , during this measurement.

Typical specifications are not production tested, but are supported by characterization data at initial product release.

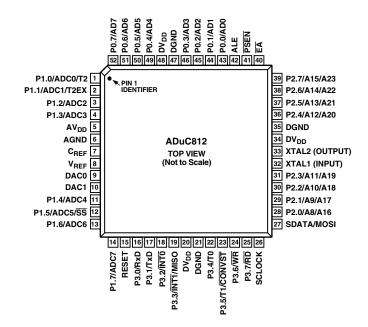
#### ABSOLUTE MAXIMUM RATINGS\*

 $(T_A = +25^{\circ}C \text{ unless otherwise noted})$ 

$AV_{DD}$ to $DV_{DD}$ 0.3 V to +0.3 V
AGND to DGND0.3 V to +0.3 V
$DV_{DD}$ to DGND, $AV_{DD}$ to AGND0.3 V to +7 V
Digital Input Voltage to DGND0.3 V, DV <sub>DD</sub> + 0.3 V
Digital Output Voltage to DGND0.3 V, DV <sub>DD</sub> + 0.3 V
$V_{REF}$ to AGND0.3 V, $AV_{DD}$ + 0.3 V
Analog Inputs to AGND0.3 V, AV <sub>DD</sub> + 0.3 V
Operating Temperature Range
Industrial (B Version)40°C to +85°C
Storage Temperature Range65°C to +150°C
Junction Temperature+150°C
$\theta_{JA}$ Thermal Impedance
Lead Temperature, Soldering
Vapor Phase (60 sec)+215°C
Infrared (15 sec)+220°C

<sup>\*</sup>Stresses above those listed under Absolute Maximum Ratings may cause permanent damage to the device. This is a stress rating only; functional operation of the device at these or any other conditions above those listed in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

#### PIN CONFIGURATION



#### **ORDERING GUIDE**

Model	Temperature	Package	Package
	Range	Description	Option
ADuC812BS	−40°C to +85°C	52-Lead Plastic Quad Flatpack	S-52

### QuickStart<sup>TM</sup> Development System

Eval-ADuC812QS

#### CAUTION

ESD (electrostatic discharge) sensitive device. Electrostatic charges as high as 4000 V readily accumulate on the human body and test equipment and can discharge without detection. Although the ADuC812 features proprietary ESD protection circuitry, permanent damage may occur on devices subjected to high energy electrostatic discharges. Therefore, proper ESD precautions are recommended to avoid performance degradation or loss of functionality.



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### PIN FUNCTION DESCRIPTIONS

Mnemonic	Type	Function
$\overline{\mathrm{DV_{DD}}}$	P	Digital Positive Supply Voltage, +3 V or +5 V nominal.
$AV_{\mathrm{DD}}$	P	Analog Positive Supply Voltage, +3 V or +5 V nominal.
$C_{REF}$	I	Decoupling pin for on-chip reference. Connect 0.1 µF between this pin and AGND.
$V_{REF}$	I/O	Reference Input/Output. This pin is connected to the internal reference through a series resistor and is the reference source for the analog-to-digital converter. The nominal internal reference voltage is 2.5 V and this appears at the pin (once the ADC or DAC peripherals are enabled). This pin can be overdriven by an external reference.
AGND	G	Analog Ground. Ground Reference point for the analog circuitry.
P1.0-P1.7	I	Port 1 is an 8-bit Input Port only. Unlike other Ports, Port 1 defaults to Analog Input Mode, to configure any of these Port Pins as a digital input, write a "0" to the port bit. Port 1 pins are multifunction and share the following functionality.
ADC0-ADC7	I	Analog Inputs. Eight single-ended analog inputs. Channel selection is via ADCCON2 SFR.
T2	I	Timer 2 Digital Input. Input to Timer/Counter 2. When Enabled, Counter 2 is incremented in response to a 1 to 0 transition of the T2 input.
T2EX	I	Digital Input. Capture/Reload trigger for Counter 2 and also functions as an Up/Down control input for Counter 2.
$\overline{SS}$	I	Slave Select input for the SPI interface.
SDATA	I/O	User selectable, I <sup>2</sup> C-Compatible Input/Output pin or SPI Data Input/Output pin.
SCLOCK	I/O	Serial Clock pin for I <sup>2</sup> C-Compatible or SPI serial interface clock.
MOSI	I/O	SPI Master Output/Slave Input Data I/O pin for SPI interface.
MISO	I/O	Master Input/Slave Output Data I/O pin for SPI Serial Interface.
DAC0	0	Voltage Output from DAC0.
DAC1	0	Voltage Output from DAC1.
RESET	I	Digital Input. A high level on this pin for 24 master clock cycles while the oscillator is running resets the device.
P3.0-P3.7	I/O	Port 3 is a bidirectional port with internal pull-up resistors. Port 3 pins that have 1s written to them are pulled high by the internal pull-up resistors, and in that state they can be used as inputs. As inputs Port 3 pins being pulled externally low will source current because of the internal pull-up resistors. Port 3 pins also
DD	1/0	contain various secondary functions which are described below.
RxD TD	I/O	Receiver Data Input (asynchronous) or Data Input/ Output (synchronous) of serial (UART) port.
$\frac{\text{TxD}}{\text{INT0}}$	0	Transmitter Data Output (asynchronous) or Clock Output (synchronous) of serial (UART) port.
	I	Interrupt 0, programmable edge or level triggered Interrupt input, which can be programmed to one of two priority levels. This pin can also be used as a gate control input to Timer 0.
ĪNT1	I	Interrupt 1, programmable edge or level triggered Interrupt input, which can be programmed to one of two priority levels. This pin can also be used as a gate control input to Timer 1.
T0	I	Timer/Counter 0 Input.
T1	I	Timer/Counter 1 Input.
CONVST	I	Active low Convert Start Logic input for the ADC block when the external Convert start function is enabled. A low-to-high transition on this input puts the track/hold into its hold mode and starts conversion.
WR	0	Write Control Signal, Logic Output. Latches the data byte from Port 0 into the external data memory.
RD	0	Read Control Signal, Logic Output. Enables the external data memory to Port 0.
XTAL2	0	Output of the inverting oscillator amplifier.
XTAL1	I	Input to the inverting oscillator amplifier and input to the internal clock generator circuits.
DGND	G	Digital Ground. Ground reference point for the digital circuitry.
P2.0–P2.7 (A8–A15) (A16–A23)	I/O	Port 2 is a bidirectional port with internal pull-up resistors. Port 2 pins that have 1s written to them are pulled high by the internal pull-up resistors, and in that state they can be used as inputs. As inputs Port 2 pins being pulled externally low will source current because of the internal pull-up resistors. Port 2 emits the high order address bytes during fetches from external program memory and middle and high order
<del>PSEN</del>	О	address bytes during accesses to the external 24-bit external data memory space.  Program Store Enable, Logic Output. This output is a control signal that enables the external program
		memory to the bus during external fetch operations. It is active every six oscillator periods except during external data memory accesses. This pin remains high during internal program execution. PSEN can also be used to enable serial download mode when pulled low through a resistor on power-up or RESET.

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Mnemonic	Type	Function
ALE	0	Address Latch Enable, Logic Output. This output is used to latch the low byte (and middle byte for 24-bit address space accesses) of the address into external memory during normal operation. It is activated every six oscillator periods except during an external data memory access.
EA	I	External Access Enable, Logic Input. When held high, this input enables the device to fetch code from internal program memory locations 0000H to 1FFFH. When held low this input enables the device to fetch all instructions from external program memory.
P0.7–P0.0 (A0–A7)	I/O	Port 0 is an 8-bit open drain bidirectional I/O port. Port 0 pins that have 1s written to them float and in that state can be used as high impedance inputs. Port 0 is also the multiplexed low order address and data bus during accesses to external program or data memory. In this application it uses strong internal pull-ups when emitting 1s.

## TERMINOLOGY ADC SPECIFICATIONS

#### **Integral Nonlinearity**

This is the maximum deviation of any code from a straight line passing through the endpoints of the ADC transfer function. The endpoints of the transfer function are zero scale, a point 1/2 LSB below the first code transition and full scale, a point 1/2 LSB above the last code transition.

#### **Differential Nonlinearity**

This is the difference between the measured and the ideal 1 LSB change between any two adjacent codes in the ADC.

#### Offset Error

This is the deviation of the first code transition (0000...000) to (0000...001) from the ideal, i.e., +1/2 LSB.

#### **Full-Scale Error**

This is the deviation of the last code transition from the ideal AIN voltage (Full Scale -1.5 LSB) after the offset error has been adjusted out.

#### Signal to (Noise + Distortion) Ratio

This is the measured ratio of signal to (noise + distortion) at the output of the A/D converter. The signal is the rms amplitude of the fundamental. Noise is the rms sum of all nonfundamental signals up to half the sampling frequency ( $f_S/2$ ), excluding dc.

The ratio is dependent upon the number of quantization levels in the digitization process; the more levels, the smaller the quantization noise. The theoretical signal to (noise +distortion) ratio for an ideal N-bit converter with a sine wave input is given by:

Signal to (Noise + Distortion) = (6.02N + 1.76) dB

Thus for a 12-bit converter, this is 74 dB.

#### **Total Harmonic Distortion**

Total Harmonic Distortion is the ratio of the rms sum of the harmonics to the fundamental.

#### DAC SPECIFICATIONS

#### **Relative Accuracy**

Relative accuracy or endpoint linearity is a measure of the maximum deviation from a straight line passing through the endpoints of the DAC transfer function. It is measured after adjusting for zero error and full-scale error.

#### **Voltage Output Settling Time**

This is the amount of time it takes for the output to settle to a specified level for a full-scale input change.

#### Digital to Analog Glitch Impulse

This is the amount of charge injected into the analog output when the inputs change state. It is specified as the area of the glitch in nV sec.

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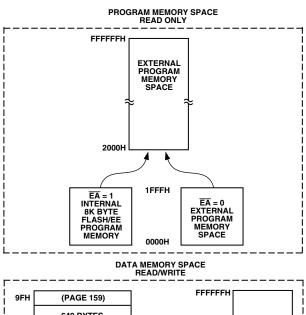
#### **ADuC812 ARCHITECTURE, MAIN FEATURES**

The ADuC812 is a highly integrated high accuracy 12-bit data acquisition system. At its core, the ADuC812 incorporates a high performance 8-bit (8051-Compatible) MCU with on-chip reprogrammable nonvolatile Flash/EE program memory controlling a multichannel (8-input channels), 12-bit ADC.

The chip incorporates all secondary functions to fully support the programmable data acquisition core. These secondary functions include User Flash/EE Data Memory, Watchdog Timer (WDT), Power Supply Monitor (PSM) and various industry-standard parallel and serial interfaces.

#### ADuC812 MEMORY ORGANIZATION

As with all 8051-compatible devices, the ADuC812 has separate address spaces for Program and Data memory as shown in Figure 1. Also as shown in Figure 1, an additional 640 Bytes of Flash/EE Data Memory are available to the user. The Flash/EE Data Memory area is accessed indirectly via a group of control registers mapped in the Special Function Register (SFR) area.



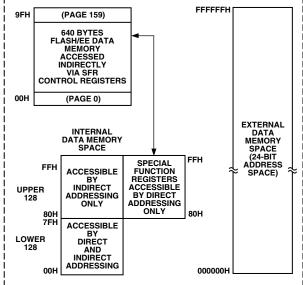


Figure 1. ADuC812 Program and Data Memory Maps

The lower 128 bytes of internal data memory are mapped as shown in Figure 2. The lowest 32 bytes are grouped into four banks of eight registers addressed as R0 through R7. The next 16 bytes (128 bits) above the register banks form a block of bit addressable memory space at bit addresses 00H through 7FH.

The SFR space is mapped in the upper 128 bytes of internal data memory space. The SFR area is accessed by direct addressing only and provides an interface between the CPU and all onchip peripherals. A block diagram showing the programming model of the ADuC812 via the SFR area is shown in Figure 3.

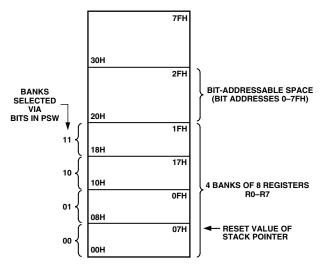


Figure 2. Lower 128 Bytes of Internal RAM

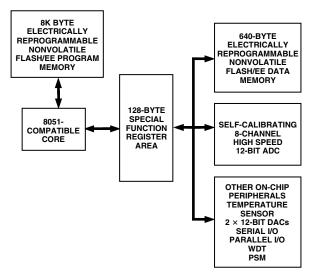


Figure 3. ADuC812 Programming Model

### ADC CIRCUIT INFORMATION General Overview

The ADC conversion block incorporates a 5  $\mu$ s, 8-channel, 12-bit, single supply A/D converter. This block provides the user with multichannel mux, track/hold, on-chip reference, calibration features and A/D converter. All components in this block are easily configured via a 3-register SFR interface.

The A/D converter consists of a conventional successive-approximation converter based around a capacitor DAC. The converter accepts an analog input range of 0 to  $+V_{REF}$ . A high precision, low drift and factory calibrated 2.5 V reference is

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provided on-chip. The internal reference may be overdriven via the external  $V_{REF}$  pin. This external reference can be in the range 2.3 V to  $AV_{\rm DD}$ .

Single step or continuous conversion modes can be initiated in software or, alternatively, by applying a convert signal to an external Pin 25 (CONVST). Timer 2 can also be configured to generate a repetitive trigger for ADC conversions. The ADC may be configured to operate in a DMA Mode whereby the ADC block continuously converts and captures samples to an external RAM space without any interaction from the MCU core. This automatic capture facility can extend through a 16 MByte external Data Memory space.

The ADuC812 is shipped with factory programmed calibration coefficients that are automatically downloaded to the ADC on power-up, ensuring optimum ADC performance. The ADC core contains internal Offset and Gain calibration registers, a software calibration routine is provided to allow the user to overwrite the factory programmed calibration coefficients if required, thus minimizing the impact of endpoint errors in the users target system.

A voltage output from an on-chip temperature sensor proportional to absolute temperature can also be routed through the front-end ADC multiplexor (effectively a 9th ADC channel input) facilitating a temperature sensor implementation.

#### **ADC Transfer Function**

The analog input range for the ADC is 0 V to  $V_{REF}$ . For this range, the designed code transitions occur midway between successive integer LSB values (i.e., 1/2 LSB, 3/2 LSBs, 5/2 LSBs . . . FS –3/2 LSBs). The output coding is straight binary with 1 LSB = FS/4096 or 2.5 V/4096 = 0.61 mV when  $V_{REF}$  = 2.5 V. The ideal input/output transfer characteristic for the 0 to  $V_{REF}$  range is shown in Figure 4.

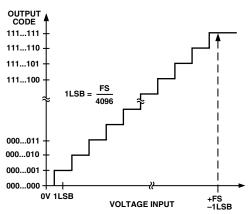


Figure 4. ADuC812 ADC Transfer Function

#### SFR Interface to ADC Block

The ADC operation is fully controlled via three SFRs, namely:

#### ADCCON1 - (ADC Control SFR #1)

The ADCCON1 register controls conversion and acquisition times, hardware conversion modes and power-down modes as detailed below.

SFR Address: EFH SFR Power-On Default Value: 20H Bit Addressable: NO

MD1	MD0	CK1	CK0	AQ1	AQ0	T2C	EXC

Table I. ADCCON1 SFR Bit Designations

Bit Location	Bit Mnemonic	Description
ADCCON1.7 ADCCON1.6	MD1 MD0	The mode bits (MD1, MD0) select the active operating mode of the ADC as follows:  MD1 MD0 Active Mode 0 0 ADC powered down. 0 1 ADC normal mode 1 0 ADC powered down if not executing a conversion cycle. 1 1 ADC standby if not executing a conver-
ADCCON1.5 ADCCON1.4	CK1 CK0	sion cycle.  The ADC clock divide bits (CK1, CK0) select the divide ratio for the master clock used to generate the ADC clock. An ADC conversion will require 16 ADC clocks in addition to the selected number of acquisition clocks (see AQ0/AQ1 below). The divider ratio is selected as follows:
		CK1 CK0 MCLK Divider 0 0 1 0 1 2 1 0 4 1 1 8
ADCCON1.3 ADCCON1.2	AQ1 AQ0	The ADC acquisition select bits (AQ1, AQ0) select the time available for the input track/hold amplifier to acquire the input signal and is selected as follows: $ \begin{array}{ccccccccccccccccccccccccccccccccccc$
ADCCON1.1	T2C	The Timer 2 conversion bit (T2C) is set to enable the Timer 2 over-flow bit to be used as the ADC convert start trigger input.
ADCCON1.0	EXC	The external trigger enable bit (EXC) is set to allow the external Pin 23 (CONVST) to be used as the active low convert start input. This input should be an active low pulse (100 ns minimum pulsewidth) at the required sample rate.  **EFF circuits are maintained on, while in

Note: In standby mode the ADC  $V_{REF}$  circuits are maintained on, while in powered down mode all ADC peripherals are powered down thus minimizing current consumption. Typical ADC current consumption is 1.6 mA at  $V_{DD}$  = 5 V.

#### ADCCON2 - (ADC Control SFR #2)

The ADCCON2 register controls ADC channel selection and conversion modes as detailed below.

SFR Address: D8H SFR Power On Default Value: 00H Bit Addressable: YES

ADCI	DMA	CCONV	SCONV	CS3	CS2	CS1	CS0

#### Table II. ADCCON2 SFR Bit Designations

Bit	Bit					
Location	Mnemonic	Desc	ripti	on		
ADCCON2.7	ADCI					it (ADCI) is
						end of a
		singl	e AD0	C con	versio	n cycle or at
		1				ck conver-
		1				by hardware
						to the ADC
			_		e Rou	
ADCCON2.6	DMA					le bit (DMA)
						itiate a pre-
			_			mode opera-
						lescription of
ADCCONA 5	CCONT			_	n belo	
ADCCON2.5	CCONV	1				ersion bit
		l `	,		•	e user to a continuous
						n this mode
						ting based on
						el configura-
						e ADCCON
				-	-	atically starts
			-			ce a previous
						ompleted.
ADCCON2.4	SCONV				ersion	
		(SCC	ONV)	is set	by the	e user to
		initia	te a s	ingle (	conve	rsion cycle.
						tomatically
					_	etion of the
					n cycl	
ADCCON2.3	CS3	l .				bits (CS3-0)
ADCCON2.2	CS2					ram the
ADCCON2.1	CS1	_				n under
ADCCON2.0	CS0					e a conver-
					he ch	
						pointed to tion bits. In
						nel selection
						annel ID
						memory.
						CH#
					0	
		0	0	0	1	1
		0	0	1	0	2
		0	0	1	1	3
		0	1	0	0	4
		0	1	0	1	5
		0	1	1	0	6
		0	1	1	1	7
		1	0	0	0	Temp Sensor
		1	X	X	X	Other
						Combinations
		1	1	1	1	DMA STOP

#### ADCCON3 - (ADC Control SFR #3)

The ADCCON3 register gives user software an indication of ADC busy status.

SFR Address: F5H
SFR Power On Default Value: 00H
Bit Addressable: NO

BUSY RSVD RSVD RSVD CTYP CAL1 CAL0 CALST

Table III. ADCCON3 SFR Bit Designations

Bit Location	Bit Mnemonic	Description
ADCCON3.7	BUSY	The ADC busy status bit (BUSY) is a read-only status bit that is set during a valid ADC conversion or calibration cycle. Busy is automatically cleared by the core at the end of conversion or calibration.
ADCCON3.6 ADCCON3.5	RSVD RSVD	ADCCON3.0-3.6 are reserved (RSVD) for internal use. These
ADCCON3.4	RSVD	bits will read as zero and should
ADCCON3.3	RSVD	only be written as zero by user
ADCCON3.2	RSVD	software.
ADCCON3.1	RSVD	
ADCCON3.0	RSVD	

#### **ADC Internal Reference**

If the internal reference is being used, both the  $V_{REF}$  and  $C_{REF}$  pins should be decoupled with 100 nF capacitors to AGND. These decoupling capacitors should be placed very close to the  $V_{REF}$  and  $C_{REF}$  pins. For specified performance, it is recommended that when using an external reference, this reference should be between 2.3 V and the analog supply  $AV_{DD}$ .

If the internal reference is required for use external to the MicroConverter, it should be buffered at the  $V_{REF}$  pin and a 100 nF capacitor should be connected from this pin to AGND.

The internal 2.5 V is factory calibrated to an absolute accuracy of 2.5 V  $\pm 50$  mV. It should also be noted that the internal V<sub>REF</sub> will remain powered down until either of the DACs or the ADC peripheral blocks are powered on by their respective enable bits.

#### Calibration

The ADC block also has four associated calibration SFRs. These SFR's drive calibration logic ensuring optimum performance from the 12-bit ADC at all times. As part of the power-on reset configuration, these SFRs are configured automatically and transparently from factory programmed calibration constants. In many applications use of factory programmed calibration constants will suffice; however, these calibration SFRs may be overwritten by user code to further compensate for system-dependent offset and gain errors.

#### **Calibration Overview**

The ADC block incorporates calibration hardware that ensures optimum performance from the ADC at all times. The calibration modes are exercised as part of the ADuC812 internal factory final test routines. The factory calibration results are stored in Flash memory and are automatically downloaded on any power-on-reset event to initialize the ADC calibration registers. In

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many applications this autocalibration download function suffices. Alternatively, a device calibration can be easily initiated by user software to compensate for significant changes in operating conditions (CLK frequency, analog input range, reference voltage and supply voltages).

This in-circuit software calibration feature allows the user to remove various system and reference related errors (whether it be internal or external reference) and to make use of the full dynamic range of the ADC by adjusting the analog input range of the part for a specific system. Contact Analog Devices, Inc. for further details on the implementation of the software calibration routine in your applications.

### ADC MODES OF OPERATION

#### **Typical Operation**

Once configured via the ADCCON 1-3 SFRs (shown previously) the ADC will convert the analog input and provide an ADC 12-bit result word in the ADCDATAH/L SFRs. The top four bits of the ADCDATAH SFR will be written with the channel selection bits to identify the channel result. The format of the ADC 12-bit result word is shown in Figure 5.

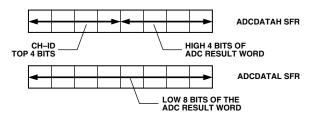


Figure 5. ADC Result Format

#### **ADC DMA Mode**

The on-chip ADC has been designed to run at a maximum speed of one sample every 5  $\mu$ s (i.e., 200 kHz sampling rate). Therefore, in an interrupt driven routine the user software is required to service the interrupt, read the ADC result and store the result for further post processing, all within 5  $\mu$ s otherwise the next ADC sample could be lost. In applications where the ADuC812 cannot sustain the interrupt rate, an ADC DMA Mode is provided.

The ADC DMA Mode is enabled via the DMA enable bit (ADCCON2.6), which allows the ADC to sample continuously as per configuration in ADCCON SFRs. Each sample result is written into an external Static RAM (mapped in the data memory space) without any interaction from the ADuC812 core. This mode ensures the ADuC812 can capture a contiguous sample stream even at full speed ADC update rates.

Before enabling ADC DMA mode the user must first configure the external SRAM to which the ADC samples will be written. This consists of writing the required ADC DMA channels into the channel ID bits (the top four bits) in the external SRAM. A typical preconfiguration of external memory is shown in Figure 6.

Once the external data memory has been preconfigured, the DMA address pointer (DMAP, DMAH and DMAL) SFRs are written. These SFRs should be written with the DMA start address in external memory. In Figure 6, for example, the DMA start address is 000000H. The 3-byte start address should be written in the following order: DMAL, DMAH and DMAP. The end of a DMA table is signified by writing "1111" into the channel selection bits field.

00000AH	1	1	1	1	STOP COMMAND
					REPEAT LAST CHANNEL
	0	0	1	1	FOR A VALID STOP
					CONDITION
	0	0	1	1	CONVERT ADC CH#3
	1	0	0	0	CONVERT TEMP SENSOR
	0	1	0	1	CONVERT ADC CH#5
000000H	0	0	1	0	CONVERT ADC CH#2

Figure 6. Typical DMA External Memory Preconfiguration

The DMA Enable bit (ADCCON2.6, DMA) can now be set to initiate the DMA conversion and transfer of the results sequentially into external memory. Remember that the DMA mode will only progress if the user has preconfigured the ADC conversion time and trigger modes via the ADCCON1 and 2 SFRs. The end of DMA conversion is signified by the ADC interrupt bit ADCCON2.7.

At the end of ADC DMA Mode, the external data memory contains the new ADC conversion results as shown in Figure 7. It should be noted that the channel selection bits are still present in the result words to identify the individual conversion results.

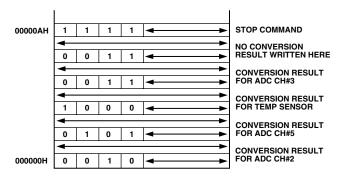


Figure 7. Typical External Memory Configuration Post ADC DMA Operation

#### Micro Operation during ADC DMA Mode

During ADC DMA mode the MicroConverter core is free to continue code execution, including general housekeeping and communication tasks. However, it should be noted that MCU core accesses to Ports 0 and 2 (which, of course, are being used by the DMA controller) are gated "OFF" during ADC DMA mode of operation. This means that even though the instruction that accesses the external Ports 0 or 2 will appear to execute, no data will be seen at these external port pins as a result.

The MicroConverter core is interrupted once the requested block of DMA data has been captured and written to external memory allowing the service routine for this interrupt to postprocess the data without any real time, timing constraints.

#### SFR Interface to the DAC Block

The ADuC812 incorporates two 12-bit DACs on-chip. DAC operation is controlled via a single control special function register and four data special function registers, namely:

DAC0L/DAC1L - Contains the lower 8-bit DAC byte.

DAC0H/DAC1H - Contains the high 4-bit DAC byte.

DACCON - Contains general purpose control bits required for DAC0 and DAC1 operation.

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In normal mode of operation each DAC is updated when the low DAC nibble (DACxL) SFR is written. Both DACs can be updated simultaneously using the SYNC bit in the DACCON SFR.

In 8-bit mode of operation, the 8-bit byte written to the DACxL registers is automatically routed to the top 8 bits of each 12-bit DAC. The bit designations of the DACCON SFR are shown below in Table IV.

SFR Address: FDH
SFR Power On Default Value: 04H
Bit Addressable: NO

ъ.

MODE	RNG1	RNG0	CLR1	CLR0	SYNC	PD1	PD0
------	------	------	------	------	------	-----	-----

Table IV. DACCON SFR Bit Designations

Bit Location	Bit Mnemonic	Description
DACCON.7	MODE	The DAC MODE bit sets the overriding operating mode for both DACs. Set to "1" = 8-bit mode (Write 8 bits to DACxL SFR. Set to "0" = 12-bit mode.
DACCON.6	RNG1	DAC1 range select bit. Set to "1" = DAC1 range 0-V <sub>DD</sub> . Set to "0" = DAC1 range 0-V <sub>REF</sub> .
DACCON.5	RNG0	DAC0 range select bit. Set to "1" = DAC0 range 0-V <sub>DD</sub> . Set to "0" = DAC0 range 0-V <sub>REF</sub> .
DACCON.4	CLR1	DAC1 clear bit. Set to "0" = DAC1 output forced to 0 V. Set to "1" = DAC1 output normal.
DACCON.3	CLR0	DAC0 clear bit. Set to "0" = DAC0 output forced to 0 V. Set to "1" = DAC0 output normal.
DACCON.2	SYNC	DAC0/1 update synchronization bit.
		When set to "1" the DAC outputs update as soon as the DACxL SFRs are written.
		The user can simultaneously update both DACs by first updating the DACxL/H SFRs while SYNC is "0."
		Both DACs will then update simultaneously when the SYNC bit is set to "1."
DACCON.1	PD1	DAC1 Power-Down Bit. Set to "1" = Power-On DAC1. Set to "0" = Power-Off DAC1.
DACCON.0	PD0	DAC0 Power-Down Bit. Set to "1" = Power-On DAC0. Set to "0" = Power-Off DAC0.

#### NONVOLATILE FLASH MEMORY

#### Flash Memory Overview

The ADuC812 incorporates Flash memory technology on-chip to provide the user with a nonvolatile, in-circuit reprogrammable, code and data memory space.

Flash memory is the newest type of nonvolatile memory technology and is based on a single transistor cell architecture. This technology is basically an outgrowth of EPROM technology and was developed through the late 1980s.

Flash memory takes the flexible in-circuit reprogrammable features of EEPROM and combines them with the space efficient/density features of EPROM (see Figure 8).

Because Flash technology is based on a single transistor cell architecture, a Flash memory array, like EPROM can be implemented to achieve the space efficiencies or memory densities required by a given design.

Like EEPROM, Flash memory can be programmed in-system at a byte level, although it must be erased first; the erase being performed in sector blocks. Thus, Flash memory is often and more correctly referred to as Flash/EE memory.

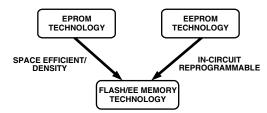


Figure 8. Flash Memory Development

Overall, Flash/EE memory represents a step closer towards the ideal memory device that includes nonvolatility, in-circuit programmability, high density and low cost. Incorporated in the ADuC812, Flash/EE memory technology allows the user to update program code space in-circuit without the need to replace one-time programmable (OTP) devices at remote operating nodes.

#### Flash/EE Memory and the ADuC812

The ADuC812 provides two arrays of Flash/EE memory for user applications.

8K bytes of Flash/EE Program space are provided on-chip to facilitate code execution without any external discrete ROM device requirements. The program memory can be programmed using conventional third party memory programmers. This array can also be programmed in-circuit, using the serial download mode provided.

A 640-Byte Flash/EE Data Memory space is also provided onchip. This may be used by the user as a general purpose nonvolatile scratchpad area. User access to this area is via a group of six SFRs. This space can be programmed at a byte level, although it must first be erased in 4-byte sectors.

#### Using the Flash/EE Program Memory

This 8K Byte Flash/EE Program Memory array is mapped into the lower 8K bytes of the 64K bytes program space addressable by the ADuC812 and will be used to hold user code in typical applications.

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The program memory array can be programmed in one of two modes, namely:

#### Serial Downloading (In-Circuit Programming)

As part of its factory boot code, the ADuC812 facilitates serial code download via the standard UART serial port. Serial download mode is automatically entered on power-up if the external pin, PSEN, is pulled low through an external resistor as shown in Figure 9. Once in this mode, the user can download code to the program memory array while the device is sited in its target application hardware. A PC serial download executable is provided as part of the ADuC812 QuickStart development system.

The Serial Download protocol is detailed in a MicroConverter Applications Note available from ADI.

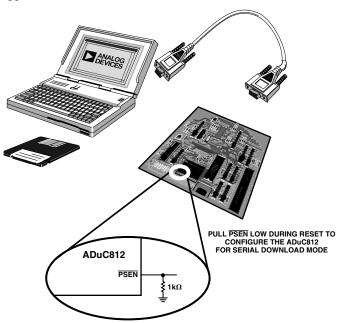


Figure 9. Flash/EE Memory Serial Download Mode Programming

#### Parallel Programming

The parallel programming mode is fully compatible with conventional third party Flash or EEPROM device programmers. A block diagram of the external pin configuration required to support parallel programming is shown in Figure 10. In this mode Ports P0, P1 and P2 operate as the external data and address bus interface, ALE operates as the Write Enable strobe and Port P3 is used as a general configuration port that configures the device for various program and erase operations during parallel programming. The high voltage (12 V) supply required for Flash programming is generated using on-chip charge pumps to supply the high voltage program lines.

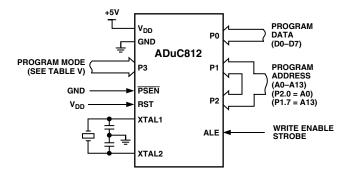


Figure 10. Flash/EE Memory Parallel Programming

Table V shows the normal parallel programming modes that can be configured using Port 3 bits.

Table V. Flash Memory Parallel Programing Modes

Port Pins (				3.0-P	3.7)			
.7	.6	.5	.4	.3	.2	.1	.0	<b>Programming Mode</b>
1	X	X	X	0	0	0	1	Erase Flash Program Erase Flash User
1	X	X	X	0	0	1	1	Read Manufacture and Chip ID
1	X	X	X	0	1	0	1	Program Byte
1	X	X	X	0	1	1	1	Read Byte
1	X	X	X	1	0	0	1	Reserved
1	X	X	X	1	0	1	1	Reserved
Any	y Oth	er Co	ode					Redundant

#### Using the Flash/EE Data Memory

The user Flash/EE data memory array consists of 640 bytes that are configured into 160 (00H to 9FH), 4-byte pages as shown in Figure 11.

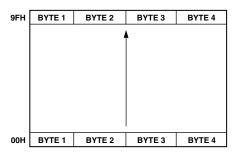


Figure 11. User Flash/EE Memory Configuration

As with other user peripherals the interface to this memory space is via a group of registers mapped in the SFR space. A group of four data registers (EDATA1-4) are used to hold the 4-byte page data just accessed. EADRL is used to hold the 8-bit address of the page to be accessed. Finally, ECON is an 8-bit control register that may be written with one of five Flash/EE memory access commands to enable various read, write, erase and verify modes.

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A block diagram of the SFR registered interface to the User Flash/EE Memory array is shown in Figure 12.

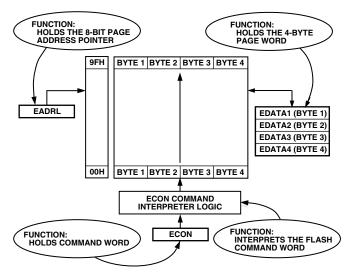


Figure 12. User Flash/EE Memory Control and Configuration

#### ECON—Flash/EE Memory Control SFR

This SFR acts as a command interpreter and may be written with one of five command modes to enable various read, program and erase cycles as detailed in Table VI:

Table VI. ECON-Flash/EE Memory Control Register Command Modes

<b>Command Byte</b>	Command Mode
01H	READ COMMAND
	Results in four bytes being read into
	EDATA 1–4 from memory page location
	contained in EADRL .
02H	WRITE COMMAND
	Results in four bytes (EDATA 1–4) being
	written to memory page location in EADRL.
	This write command assumes the de-
0211	signated "write" page has been pre-erased.
03H	RESERVED COMMAND "DO NOT USE"
0411	VERIFY COMMAND
04H	Allows the user to verify if data in EDATA
	1–4 is contained in page location designated
	by EADRL. A subsequent read of the
	ECON SFR will result in a "zero" being
	read if the verification is valid, a nonzero
	value will be read to indicate an invalid
	verification.
05H	ERASE COMMAND
	Results in an erase of the 4-byte page
	designated in EADRL.
06H	ERASE-ALL COMMAND
	Results in erase of the full user memory
	160-page (640 bytes) array.
07H to FFH	RESERVED COMMANDS
	Commands reserved for future use.

#### Flash/EE Memory Write and Erase Times

The typical program/erase times for the User Flash/EE Memory are:

Erase Full Array (640 Bytes) – 20 ms Erase Single Page (4 Bytes) – 20 ms Program Page (4 Bytes) – 250 µs

Read Page (4 Bytes) – Within Single Instruction Cycle

#### Using the Flash/EE Memory Interface

As with all Flash/EE memory architectures, the array can be programmed in system at a byte level, although it must be erased first; the erasure being performed in page blocks (4-byte pages in this case).

A typical access to the Flash/EE array will involve setting up the page address to be accessed in the EADRL SFR, configuring the EDATA1-4 with data to be programmed to the array (the EDATA SFRs will not be written for read accesses) and finally writing the ECON command word which initiates one of the five modes shown in Table VI.

It should be noted that a given mode of operation is initiated as soon as the command word is written to the ECON SFR. At this time the core microcontroller operation on the ADuC812 is idled until the requested Program/Read or Erase mode is completed.

In practice, this means that even though the Flash/EE memory mode of operation is typically initiated with a 2 machine cycle MOV instruction (to write to the ECON SFR), the next instruction will not be executed until the Flash/EE operation is complete (250  $\mu s$  or 20 ms later). This means that the core will not respond to Interrupt requests until the Flash/EE operation is complete, although the core peripheral functions like Counter/Timers will continue to count and time as configured throughout this pseudo-idle period.

#### **ERASE-ALL**

Although the 640-byte User Flash/EE array is shipped from the factory pre-erased, i.e., Byte locations set to FFH, it is nonetheless good programming practice to include an erase-all routine as part of any configuration/setup code running on the ADuC812.

An "ERASE-ALL" command consists of writing "06H" to the ECON SFR, which initiates an erase of all 640 byte locations in the Flash/EE array. This command coded in 8051 assembly would appear as:

MOV ECON, #06H ; Erase all Command ; 20 ms Duration

#### PROGRAM A BYTE

In general terms, a byte in the Flash/EE array can only be programmed if it has previously been erased. To be more specific, a byte can only be programmed if it already holds the value FFH. Because of the Flash/EE architecture this erasure must happen at a page level, therefore a minimum of four bytes (1 page) will be erased when an erase command is initiated.

A more specific example of the Program-Byte process is shown graphically in Figure 13. In this example the user will write F3H into the second byte on Page 03H of the User Flash/EE Memory space.

However, Page 03H already contains four bytes of valid data, and as the user is only required to modify one of these bytes, the full page must be first read so that this page can then be erased without the existing data being lost.

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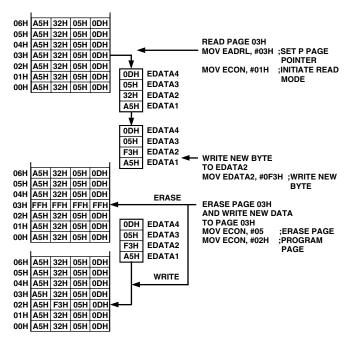


Figure 13. User Flash/EE Memory Program Byte Example

The new byte is then written to the EDATA2 SFR, followed by an ERASE cycle that will ensure this page is erased before the new page data EDATA1-4 is written back into memory.

If the user attempts to initiate a PROGRAM cycle (ECON set to 02H) without an ERASE cycle (ECON set to 05H), then only bit locations set to a "1" would be modified, i.e., the Flash/EE memory byte location must be pre-erased to allow a valid write access to the array. It should also be noted that the time durations for an ERASE-ALL command (640 bytes) and that for an ERASE page command (four bytes) are identical, i.e., 20 ms.

This example coded in 8051 assembly would appear as:

VOM	EADRL, #03H	; Set Page Pointer
MOV	ECON, #01H	; Read Page Command
MOV	EDATA2, #0F3H	; Write New Byte
MOV	ECON, #02H	; Erase Page Command
MOV	ECON, #05H	; Program Page Command

#### INTERRUPT SYSTEM

The ADuC812 provides nine interrupt sources with two priority levels. Interrupt priority within a given level is shown in descending order of priority in Figure 14, which gives a general overview of the interrupt sources and illustrates the request and control flags. The interrupt vector addresses for corresponding interrupts are also included in Table VII.

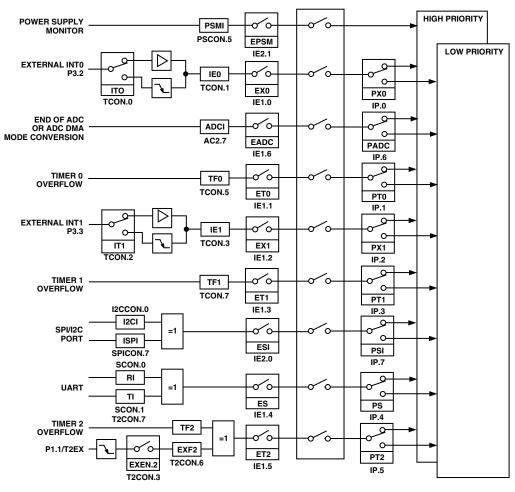


Figure 14. Interrupt Request Sources

Table VII. Interrupt Vector Addresses

Interrupt	Interrupt Name	Interrupt Vector Address	Priority Within Level
PSMI	Power Supply Monitor	43H	1
IE0	External INT0	03H	2
ADCI	End of ADC Conversion	33H	3
TF0	Timer 0 Overflow	0BH	4
IE1	External INT1	13H	5
TF1	Timer 1 Overflow	1BH	6
I2CI/ISPI	Serial Interrupt	3BH	7
RI/TI	UART Interrupt	23H	8
TF2/EXF2	Timer 2 Interrupt	2BH	9

#### Use of Interrupts

To use any of the interrupts on the ADuC812, the following three steps must be taken.

- 1. Locate the interrupt service routine at the corresponding Vector Address of that interrupt. See Table VII above.
- 2. Set the EA (enable all) bit in the IE SFR to "1."
- 3. Set the corresponding individual interrupt bit in the IE or IE2 SFR to "1."

Three SFRs are used to enable and set priority for the various interrupts. The bit designations of these SFRs are shown in Tables VIII, IX and X. It should be noted that while IE and IP SFRs are bit addressable, IE2 is byte addressable only.

#### IE - (Interrupt Enable SFR)

The IE register enables the interrupt system and seven interrupt sources.

SFR Address:
SFR Power On Default Value:
00H
Bit Addressable:
YES

EA	EADC	ET2	ES	ET1	EX1	ET0	EX0

Table VIII. Interrupt Enable (IE) SFR Bit Designations

Bit	Bit	
Location	Mnemonic	Description
IE.7	EA	The Global Interrupt Enable bit (EA) must be set to "1" before any interrupt source will be recognized by the core. EA is set to "0" to disable all interrupts.
IE.6	EADC	The ADC Interrupt Enable bit (EADC) is set to "1" to enable the ADC interrupt.
IE.5	ET2	The Timer 2 Overflow Interrupt Enable bit (ET2) is set to "1" to enable the Timer 2 interrupt.
IE.4	ES	The UART Serial Port Interrupt Enable bit (ES) is set to "1" to en- able the UART Serial Port Interrupt.
IE.3	ET1	The Timer 1 Overflow Interrupt Enable bit (ET1) is set to "1" to enable the Timer 1 interrupt.
IE.2	EX1	The INT1 Interrupt Enable bit (EX1) is set to "1" to enable the external INT1 interrupt.

Bit Location	Bit Mnemonic	Description
IE.1	ЕТ0	The Timer 0 Overflow Interrupt Enable bit (ET0) is set to "1" to enable the Timer 0 interrupt.
IE.0	EX0	The INT0 Interrupt Enable bit (EX0) is set to "1" to enable the external INT0 interrupt

#### IE2 - (Interrupt Enable 2 SFR)

The IE2 register enables two additional interrupt sources.

SFR Address: A9H SFR Power On Default Value: 00H Bit Addressable: NO

NU NU	NU	NU	NU	NU	<b>EPSM</b>	<b>ESI</b>
-------	----	----	----	----	-------------	------------

Table IX. Interrupt Enable 2 (IE2) SFR Bit Designations

Bit Location	Bit Mnemonic	Description
IE2.7 IE2.6 IE2.5 IE2.4 IE2.3 IE2.2	NU NU NU NU NU NU	Not Used Not Used Not Used Not Used Not Used Not Used
IE2.1 IE2.0	EPSM ESI	The Power Supply Monitor Interrupt enable bit is set to "1" to enable the PSM Interrupt. The SPI/I <sup>2</sup> C Interrupt Enable bit (ESI) is set to "1" to enable the SPI or I <sup>2</sup> C interrupt.

#### IP - (Interrupt Priority SFR)

The IP register sets one of two main priority levels for the various interrupt sources. Set the corresponding bit to "1" to configure interrupt as high priority and to "0" to configure interrupt as low priority.

SFR Address: B8H SFR Power On Default Value: 00H Bit Addressable: YES

PS <sub>1</sub>	PADC	PT2	PS	PT1	PX1	PT0	PX0
-----------------	------	-----	----	-----	-----	-----	-----

Table X. Interrupt Priority (IP) SFR Bit Designations

Bit Location	Bit Mnemonic	Description
IP.7	PSI	Sets SPI/I <sup>2</sup> C Interrupt Priority
IP.6	PADC	Sets ADC Interrupt Priority
IP.5	PT2	Sets Timer 2 Interrupt Priority
IP.4	PS	Sets UART Serial Port Interrupt
		Priority
IP.3	PT1	Sets Timer 1 Interrupt Priority
IP.2	PX1	Sets External INT1 Interrupt
		Priority
IP.1	PT0	Sets Timer 0 Interrupt Priority
IP.0	PX0	Sets External INT0 Interrupt
		Priority

#### ON-CHIP PERIPHERALS

The following sections give a brief overview of the various secondary peripherals also available on-chip. A quick reference to the various SFR configuration registers used to control these peripheral functions is given on the following pages.

#### PARALLEL I/O PORTS 0-3

The ADuC812 uses four general purpose data ports to exchange data with external devices. In addition to performing general purpose I/O, some ports are capable of external memory operations; others are multiplexed with an alternate function for the peripheral features on the device. In general, when a peripheral sharing a port pin is enabled, that pin may not be used as a general purpose I/O pin.

Ports 0, 2 and 3 are bidirectional while Port 1 is an input only port. All ports contain an output latch and input buffer, the I/O Ports will also contain an output driver. Read and Write accesses to Port 0–3 pins are performed via their corresponding special function registers.

Port pins on Ports 0, 2 and 3 can be independently configured as digital inputs or digital outputs via the corresponding port SFR bits. Port 1 pins however, can be configured as digital inputs or analog inputs only, Port 1 digital output capability is not supported on this device.

#### SERIAL I/O PORTS

#### **UART Interface**

The serial port is full duplex, meaning it can simultaneously transmit and receive. It is also receive-buffered, meaning it can commence reception of a second byte before a previously received byte has been read from the receive register. However, if the first byte still hasn't been read by the time reception of the second byte is complete, one of the bytes will be lost.

The physical interface to the serial data network is via Pins RxD(P3.0) and TxD(P3.1) and the serial port can be configured into one of four modes of operation.

#### Serial Peripheral Interface (SPI)

The Serial Peripheral Interface (SPI) is an industry standard synchronous serial interface that allows eight bits of data to be synchronously transmitted and received simultaneously. The system can be configured for Master or Slave operation.

#### I<sup>2</sup>C-Compatible Serial Interface

The ADuC812 supports a 2-wire serial interface mode that is  $I^2C$ -compatible. This interface can be configured to be a Software Master or Hardware Slave and is multiplexed with the SPI serial interface port.

#### TIMERS/COUNTERS

The ADuC812 has three 16-bit Timer/Counters, namely: Timer 0, Timer 1 and Timer 2. The Timer/Counter hardware has been included on-chip to relieve the processor core of the overhead inherent in implementing timer/counter functionality in software. Each Timer/Counter consists of two 8-bit registers THx and TLx (x = 0, 1 and 2). All three can be configured to operate either as timers or event counters.

In "Timer" function, the TLx register is incremented every machine cycle. Thus one can think of it as counting machine cycles. Since a machine cycle consists of 12 oscillator periods, the maximum count rate is 1/12 of the oscillator frequency.

In "Counter" function, the TLx register is incremented by a 1-to-0 transition at its corresponding external input pin, T0, T1 or T2.

#### **ON-CHIP MONITORS**

The ADuC812 integrates two on-chip monitor functions to minimize code or data corruption during catastrophic programming or other external system faults. Again, both monitor functions are fully configurable via the SFR space.

#### WATCHDOG TIMER

The purpose of the watchdog timer is to generate a device reset within a reasonable amount of time if the ADuC812 enters an erroneous state, possibly due to a programming error, electrical noise or RFI. The Watchdog function can be permanently disabled by clearing WDE (Watchdog Enable) bit in the Watchdog Control (WDCON) SFR. When enabled, the watchdog circuit will generate a system reset if the user program fails to refresh the watchdog within a predetermined amount of time. The watchdog reset interval can be adjusted via the SFR prescale bits from 16 to 204 ms.

#### POWER SUPPLY MONITOR

The Power Supply Monitor generates an interrupt when the analog  $(AV_{DD})$  or digital  $(DV_{DD})$  power supplies to the ADuC812 drop below one of five user-selectable voltage trip points from 2.6 V to 4.6 V The interrupt bit will not be cleared until the power supply has returned above the trip point for at least 256 ms.

This monitor function ensures that the user can save working registers to avoid possible data corruption due to the low supply condition, and that code execution will not resume until a "safe" supply level has been well established. The supply monitor is also protected against spurious glitches triggering the interrupt circuit.

#### **QuickStart DEVELOPMENT SYSTEM**

The QuickStart Development System is a full featured, low cost development tool suite supporting the ADuC812. The system consists of the following PC-based (Win95-compatible) hardware and software development tools.

Code Development: Full Assembler and C Compiler (2K Code Limited)

Code Functionality: ADSIM812, Windows Code Simulator Code Download: FLASH/EE UART-Serial Downloader

Code Debug: Serial Port Debugger

Misc: System includes CD-ROM documentation, power supply and serial port cable.

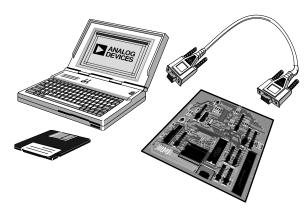
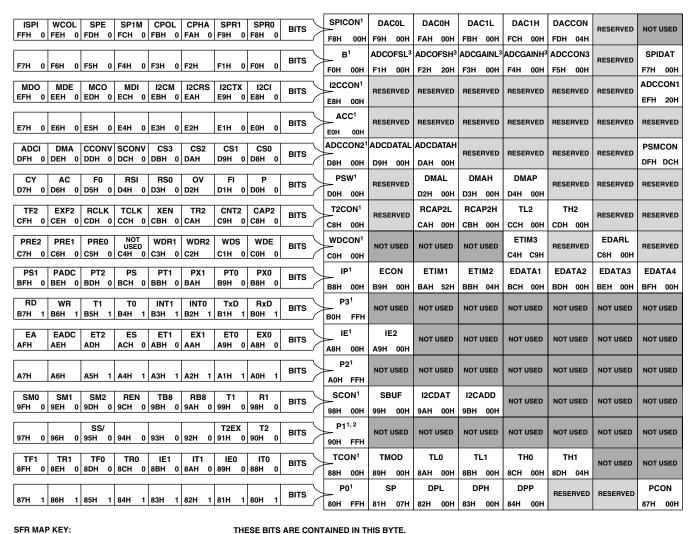


Figure 15. Typical QuickStart System Configuration

#### SPECIAL FUNCTION REGISTERS

All registers except the program counter and the four general purpose register banks, reside in the special function register (SFR) area. The SFR registers include control, configuration and data registers that provide an interface between the CPU and other onchip peripherals.

Figure 16 shows a full SFR memory map and SFR contents on Reset; NOT USED indicates unoccupied SFR locations. Unoccupied locations in the SFR address space are not implemented; i.e., no register exists at this location. If an unoccupied location is read, an unspecified value is returned. SFR locations reserved for on-chip testing are shaded (RESERVED) and should not be accessed by user software.



#### SFR MAP KEY:

#### **TCON**◀ MNEMONIC MNEMONIC →IF0 ITO **DEFAULT VALUE** <del>}►</del>89H 0 88H SFR ADDRESS 88H 00H **DEFAULT VALUE** SFR ADDRESS

Figure 16. Special Function Register Locations and Reset Values

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#### SFR NOTES:

<sup>1</sup>SFRs whose address ends in 0H or 8H are bit addressable.

<sup>2</sup>THE PRIMARY FUNCTION OF PORT1 IS AS AN ANALOG INPUT PORT, THEREFORE, TO ENABLE THE DIGITAL SECONDARY FUNCTIONS ON THESE PORT PINS, WRITE A '0' TO THE CORRESPONDING PORT 1 SFR BIT.

3CALIBRATION COEFFICIENTS ARE PRECONFIGURED ON POWER-UP TO FACTORY CALIBRATED VALUES.

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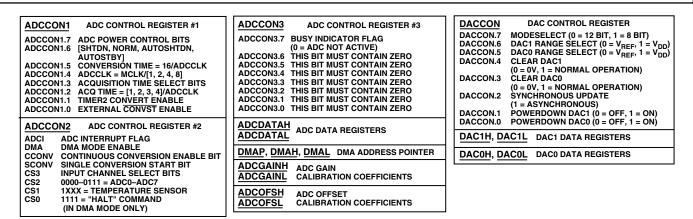


Figure 17. ADC and DAC—Control and Configuration SFRs

<u>P0</u>	PORT0 REGISTER (ALSO A0-A7 & D0-D7)	<u>SBUF</u>	SERIAL PORT BUFFER REGISTER	WDCON WATCHDOG TIME
P1 T2EX T2 P2	PORT1 REGISTER (ANALOG & DIGITAL INPUTS) TIMER/COUNTER 2 CAPTURE/RELOAD TRIGGER TIMER/COUNTER 2 EXTERNAL INPUT PORT2 REGISTER (ALSO A8-A15 & A16-A23)	PCON.3	ALE DISABLE (0 = NORMAL, 1 = FORCES ALE HIGH) GENERAL PURPOSE FLAG	CONTROL REGISTER PRE2 WATCHDOG TIMEOUT SELECTION BITS PRE1 TIMEOUT = [16, 32, 64, 128, 256, 512, 1024, PRE0 2048] ms WDR1 WATCHDOG TIMER REFRESH BITS WDR2 SET SEQUENTIALLY TO REFRESH
P3 RD WR T1 T0	PORT3 REGISTER EXTERNAL DATA MEMORY READ STROBE EXTERNAL DATA MEMORY WRITE STROBE TIMER/COUNTER 1 EXTERNAL INPUT TIMER/COUNTER 0 EXTERNAL INPUT	PCON.1	ON.2 GENERAL PURPOSE FLAG ON.1 POWER-DOWN CONTROL BIT (RECOVERABLE WITH HARD RESET) ON.0 IDLE-MODE CONTROL (RECOVERABLE WITH ENABLED)	WATCHDOG WDS WATCHDOG STATUS FLAG WDE WATCHDOG ENABLE  PSMCON POWER SUPPLY MONITOR CONTROL REGISTER
INT1 INT0 TxD RxD	EXTERNAL INTERRUPT 1 EXTERNAL INTERRUPT 0 SERIAL PORT TRANSMIT DATA LINE SERIAL PORT RECEIVE DATA LINE	PSW CY AC F0	PROGRAM STATUS WORD CARRY FLAG AUXILIARY CARRY FLAG GENERAL PURPOSE FLAG 0	PSMCON.7 (NOT USED) PSMCON.6 PSM STATUS BIT (1 = NORMAL/0 = FAULT) PSMCON.5 PSM INTERRUPT BIT
SCON SM0 SM1	SERIAL COMMUNICATIONS CONTROL REGISTER	RS1 RS0 OV F1 P	REGISTER BANK SELECT CONTROL BITS ACTIVE REGISTER BANK = [0, 1, 2, 3] OVERFLOW FLAG GENERAL PURPOSE FLAG 1 PARITY OF ACC DATA POINTER PAGE	PSMCON.4 TRIP POINT SELECT BITS PSMCON.3 [4.63V, 4.37V, 3.08V, 2.93V, 2.63V] PSMCON.1 AVDD/DVDD FAULT INDICATOR (1 = ADD/0 = DVDD) PSMCON.0 PSM POWERDOWN CONTROL (1 = ON/0 = OFF)
SM2 REN TB8 RB8 TI	RATE/32 (×2) IN MODES 2&3, ENABLES MULTIPROCESSOR COMMUNICATION RECEIVE ENABLE CONTROL BIT IN MODES 2&3, 9TH BIT TRANSMITTED IN MODES 2&3, 9TH BIT RECEIVED TRANSMIT INTERRUPT FLAG	DPH, D ACC B SP	PL (DPTR) DATA POINTER ACCUMULATOR  STACK POINTER	ECON DATA FLASH MEMORY COMMAND REGISTER  01h READ 04h VERIFY 02h WRITE 05h ERASE 03h (RESERVED) 06h ERASE ALL
RI	RECEIVE INTERRUPT FLAG			EADRL DATA FLASH MEMORY ADDRESS REGISTER  EDATA1, EDATA2, EDATA3, EDATA4 DATA FLASH DATA REGISTERS  ETIM1, ETIM2, ETIM3 FLASH TIMING REGISTERS

Figure 18. 8051 Core, On-Chip Monitors and Flash/EE Data Memory SFRs

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IE EA	INTERRUPT ENABLE REGISTER #1	TCON TIMER CONTROL REGISTER	SPICON SPI CONTROL REGISTER
EA	ENABLE INTURRUPTS	TF1 TIMER1 OVERFLOW FLAG	ISPI SPI INTERRUPT
1	(0 = ALL INTERRUPTS DISABLED)	(AUTO CLEARED ON VECTOR TO ISR)	(SET AT END OF SPI TRANSFER)
EADC	ENABLE ADCI (ADC INTERRUPT)	TR1 TIMER1 RUN CONTROL (0 = OFF, 1 = RUN)	WCOL WRITE COLLISION ERROR FLAG
ET2	ENABLE TF2/EXF2	TF0 TIMER0 OVERFLOW FLAG	SPE SPI ENABLE
1	(TIMER2 OVERFLOW INTERRUPT)	(AUTO CLEARED ON VECTOR TO ISR)	(0 = DISABLE, ALSO ENABLES SPI)
ES	ÉNABLE RI/TI (SERIAL PORT INTÉRRUPT)	TR0 TIMER0 RUN CONTROL (0 = OFF, 1 = RUN)	SPIM MASTER MODE SELECT (0 = SLAVE)
ET1	ENABLE TF1 (TIMER1 OVERFLOW INTERRUPT)	IE1 EXTERNAL INT1 FLAG	CPOL CLOCK POLARITY SELECT
EX1	ENABLE IE1 (EXTERNAL INTERRUPT 1)	(AUTO CLEARED ON VECTOR TO ISR)	(0 = SCLK IDLES LOW)
ET0	ENABLE TFO (TIMERO OVERFLOW INTERRUPT)	IT1 IE1 TYPE (0 = LEVEL TRIG, 1 = EDGE TRIG)	CPHA CLOCK PHASE SELECT
EX0	ENABLE IE0 (EXTERNAL INTERRUPT 0)	IEO EXTERNAL INTO FLAG	(0 = LEADING EDGE LATCH)
IE2	INTERRUPT ENABLE REGISTER #2	(AUTO CLEARED ON VECTOR TO ISR)	SPR1 SPI BITRATE SELECT BITS
IE2.1		ITO IEO TYPE (0 = LEVEL TRIG, 1 = EDGE TRIG)	SPR0 BITRATE = F <sub>OSC</sub> / [4, 8, 32, 64]
152.1	ENABLE PSMI (POWER SUPPLY MONITOR INTERRUPT)	TH0, TL0 TIMER0 REGISTERS	SPIDAT SPI DATA REGISTER
IE2.0	ENABLE ISPI/I2CI	THO, TEO TIMENOTICALOTERIO	OTIDAT STIDATA REGISTER
IEZ.U	(SERIAL INTERFACE INTERRUPT)	TH1, TL1 TIMER1 REGISTERS	I2CCON I2C CONTROL REGISTER
	(SENIAL INTENFACE INTENHOFT)		J   <del></del>
IP	INTERRUPT PRIORITY REGISTER	T2CON TIMER2 CONTROL REGISTER	MDO   MASTER MODE SDATA OUTPUT BIT   MDE   MASTER MODE SDATA OUTPUT
PSI	PRIORITY OF ISI/ISPI	TF2 OVERFLOW FLAG	ENABLE
1.0.	(SERIAL INTERFACE INTERRUPT)	EXF2 EXTERNAL FLAG	MCO MASTER MODE SCLK BIT
PADC	PRIORITY OF ADCI (ADC INTERRUPT)	RCLK RECEIVE CLOCK ENABLE	MDI MASTER MODE SDATA INPUT BIT
PT2	PRIORITY OF TF2/EXF2	(0 = TIMER1 USED FOR RxD CLK)	12CM MASTER MODE SELECT
1	(TIMER2 OVERFLOW INTERRUPT)	TCLK TRANSMIT CLOCK ENABLE	12CRS SERIAL PORT RESET
PS	PRIORITY OF RI/TI (SERIAL PORT INTERRUPT)	(0 = TIMER1 USED FOR TxD CLK)	12CTX TRANSMISSION DIRECTION STATUS
PT1	PRIORITY OF TF1	EXEN2 EXTERNAL ENABLE	I <sup>2</sup> CI SERIAL INTERFACE INTERRUPT
1	(TIMER1 OVERFLOW INTERRUPT)	(0 = IGNORE T2EX, 1 = CAP/RL)	TOT GETTIAE INTERN AGE INTERNIOR T
PX1	PRIORITY OF IE1 (EXTERNAL INT1)	TR2 RUN CONTROL (0 = STOP, 1 = RUN)	I2CADD I2C ADDRESS REGISTER
PT0	PRIORITY OF TF0	CNT2 TIMER/COUNTER SELECT	
	(TIMERO OVERFLOW INTERRUPT)	(0 = TIMER, 1 = COUNTER)	I2CDAT   I2C DATA REGISTER
PX0	PRIORITY OF IE0 (EXTERNAL INTO)	CAP2 CAPTURE/RELOAD SELECT	
T110		(0 = RELOAD, 1 = CAPTURE)	
TMOL		TH2, TL2 TIMER2 REGISTER	1
TMOD		IIIZ, ILZ IIWLEZ REGISTER	
TMOD		RCAP2H, RCAP2L TIMER2 CAPTURE/RELOAD	
TMOD			J
TMOD			
1	2 × 8 BIT T]		
(UPPE	R NIBBLE = TIMER1, LOWER NIBBLE = TIMER2)		

Figure 19. Interrupt, Timer, SPI and I<sup>2</sup>C Control SFRs

# TIMING SPECIFICATIONS 1, 2, 3 $AV_{DD} = DV_{DD} = +3.0 \text{ V or } 5.0 \text{ V} \pm 10\%$ . All specifications $T_A = T_{MIN}$ to $T_{MAX}$ unless otherwise noted.

			12 MHz		Var	iable Clo	ck		
Parameter		Min	Typ	Max	Min	Typ	Max	Units	Figure
CLOCK IN	PUT (External Clock Driven XTAL1)								
$t_{CK}$	XTAL1 Period		83.33		62.5		1000	ns	20
$t_{CKL}$	XTAL1 Width Low	20			20			ns	20
$t_{CKH}$	XTAL1 Width High	20			20			ns	20
$t_{CKR}$	XTAL1 Rise Time			20			20	ns	20
$t_{CKF}$	XTAL1 Fall Time			20			20	ns	20
${t_{CKF}_{CYC}}^4$	ADuC812 Machine Cycle Time		1			$12t_{CK}$		μs	

#### NOTES

<sup>&</sup>lt;sup>4</sup>ADuC812 Machine Cycle Time is nominally defined as MCLKIN/12.

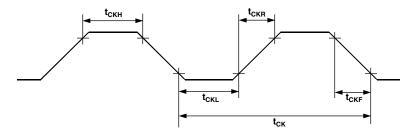


Figure 20. XTAL 1 Input

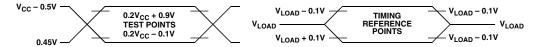


Figure 21. Timing Waveform Characteristics

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<sup>1</sup>AC inputs during testing are driven at DVDD - 0.5 V for a Logic 1 and 0.45 V for a Logic 0. Timing measurements are made at VIH min for a Logic 1 and VIL max for a Logic 0.

<sup>&</sup>lt;sup>2</sup>For timing purposes, a port pin is no longer floating when a 100 mV change from load voltage occurs. A port pin begins to float when a 100 mV change from the loaded  $V_{OH}/V_{OL}$  level occurs.  $^{3}C_{LOAD}$  for Port0, ALE,  $\overline{PSEN}$  outputs = 100 pF;  $C_{LOAD}$  for all other outputs = 80 pF unless otherwise noted.

		12	MHz	Variable	Clock		
Parameter		Min	Max	Min	Max	Units	Figure
EXTERNA	L PROGRAM MEMORY						
$t_{LHLL}$	ALE Pulsewidth	127		$2t_{CK} - 40$		ns	22
$t_{AVLL}$	Address Valid to ALE Low	43		$2t_{CK} - 40$ $t_{CK} - 40$		ns	22
$t_{LLAX}$	Address Hold After ALE Low	53		$t_{CK} - 30$		ns	22
$t_{LLIV}$	ALE Low to Valid Instruction In		234		$4t_{CK} - 100$	ns	22
$t_{LLPL}$	ALE Low to PSEN Low	53		$t_{CK} - 30$		ns	22
$t_{PLPH}$	PSEN Pulsewidth	205		$t_{CK} - 30$ $3t_{CK} - 45$		ns	22
$t_{PLIV}$	PSEN Low to Valid Instruction In		145		$3t_{CK} - 105$	ns	22
$t_{PXIX}$	Input Instruction Hold After PSEN	0		0		ns	22
$t_{PXIZ}$	Input Instruction Float After PSEN		59		$t_{\rm CK}-25$	ns	22
t <sub>AVIV</sub>	Address to Valid Instruction In		312		t <sub>CK</sub> – 25 5t <sub>CK</sub> – 105	ns	22
$t_{PLAZ}$	PSEN Low to Address Float		25		25	ns	22
$t_{PHAX}$	Address Hold After $\overline{\text{PSEN}}$ High	0		0		ns	22

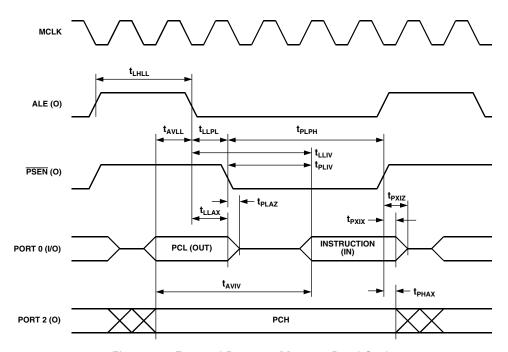


Figure 22. External Program Memory Read Cycle

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		12 N	ИHz	Variable C	lock		
Parameter		Min	Max	Min	Max	Units	Figure
EXTERNAL	L DATA MEMORY READ CYCLE						
t <sub>RLRH</sub>	RD Pulsewidth	400		6t <sub>CK</sub> – 100		ns	23
$t_{AVLL}$	Address Valid After ALE Low	43		$t_{\rm CK} - 40$		ns	23
$t_{LLAX}$	Address Hold After ALE Low	48		$t_{\rm CK}-35$		ns	23
$t_{RLDV}$	RD Low to Valid Data In		252		$5t_{CK} - 165$	ns	23
$t_{RHDX}$	Data and Address Hold After $\overline{\text{RD}}$	0		0		ns	23
$t_{RHDZ}$	Data Float After RD		97		$2t_{CK}-70$	ns	23
$t_{\rm LLDV}$	ALE Low to Valid Data In		517		$8t_{CK} - 150$	ns	23
$t_{ m AVDV}$	Address to Valid Data In		585		$9t_{CK} - 165$	ns	23
$t_{ m LLWL}$	ALE Low to $\overline{RD}$ or $\overline{WR}$ Low	200	300	$3t_{CK} - 50$	$3t_{CK} + 50$	ns	23
$t_{AVWL}$	Address Valid to $\overline{RD}$ or $\overline{WR}$ Low	203		$4t_{CK} - 130$		ns	23
$t_{RLAZ}$	RD Low to Address Float		0		0	ns	23
$t_{\mathrm{WHLH}}$	$\overline{\mathrm{RD}}$ or $\overline{\mathrm{WR}}$ High to ALE High	43	123	$t_{\rm CK}-40$	$6t_{CK}-100$	ns	23

# MCLK \_\_\_\_\_\_

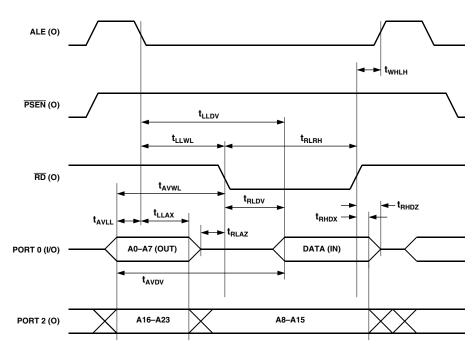


Figure 23. External Data Memory Read Cycle

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		12 N	ИHz	Variable C	lock		
Parameter		Min	Max	Min	Max	Units	Figure
EXTERNAL	L DATA MEMORY WRITE CYCLE						
$t_{WLWH}$	WR Pulsewidth	400		6t <sub>CK</sub> – 100		ns	24
$t_{AVLL}$	Address Valid After ALE Low	43		t <sub>CK</sub> - 40		ns	24
$t_{LLAX}$	Address Hold After ALE Low	48		t <sub>CK</sub> – 35		ns	24
$t_{LLWL}$	ALE Low to $\overline{\mathrm{RD}}$ or $\overline{\mathrm{WR}}$ Low	200	300	$3t_{CK} - 50$	$3t_{CK} + 50$	ns	24
$t_{AVWL}$	Address Valid to $\overline{\text{RD}}$ or $\overline{\text{WR}}$ Low	203		$4t_{CK} - 130$		ns	24
$t_{QVWX}$	Data Valid to $\overline{ m WR}$ Transition	33		t <sub>CK</sub> - 50		ns	24
$t_{QVWH}$	Data Setup Before $\overline{WR}$	433		$7t_{CK} - 150$		ns	24
$t_{WHQX}$	Data and Address Hold After $\overline{ m WR}$	33		$t_{\rm CK} - 50$		ns	24
t <sub>WHLH</sub>	$\overline{\mathrm{RD}}$ or $\overline{\mathrm{WR}}$ High to ALE High	43	123	t <sub>CK</sub> - 40	$6t_{CK} - 100$	ns	24

# MCLK \_\_\_\_\_\_\_

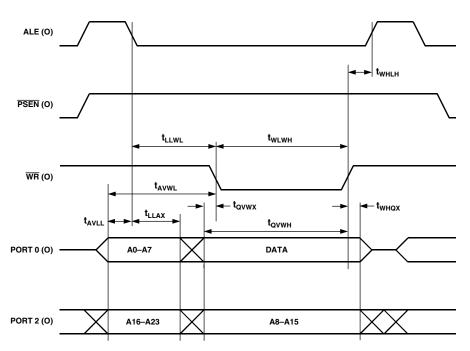


Figure 24. External Data Memory Write Cycle

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			12 MH	z	V	ariable Clock	ζ		
Parameter		Min	Typ	Max	Min	Typ	Max	Units	Figure
UART TIM	IING (Shift Register Mode)								
$t_{XLXL}$	Serial Port Clock Cycle Time		1.0			$12t_{CK}$		μs	25
$t_{OVXH}$	Output Data Setup to Clock	700			$10t_{\rm CK}-1$	133		ns	25
t <sub>DVXH</sub>	Input Data Setup to Clock	300			$2t_{CK} + 1$	33		ns	25
$t_{XHDX}$	Input Data Hold After Clock	0			0			ns	25
$t_{\rm XHQX}$	Output Data Hold After Clock	50			2t <sub>CK</sub> - 1	17		ns	25

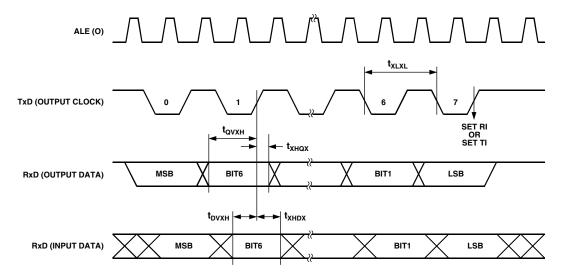


Figure 25. UART Timing in Shift Register Mode

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Parameter	r	Min	Max	Units	Figure
I <sup>2</sup> C COMI	PATIBLE INTERFACE TIMING				
$t_{\rm L}$	SCLOCK Low Pulsewidth	4.7		μs	26
$t_{H}$	SCLOCK High Pulsewidth	4.0		μs	26
$t_{SHD}$	Start Condition Hold Time	0.6		μs	26
$t_{ m DSU}$	Data Setup Time	100		ns	26
$t_{ m DHD}$	Data Hold Time	0	0.9	μs	26
$t_{RSU}$	Setup Time for Repeated Start	0.6		μs	26
$t_{PSU}$	Stop Condition Setup Time	0.6		μs	26
$t_{ m BUF}$	Bus Free Time Between a STOP				
	Condition and a START Condition	1.3		μs	26
$t_R$	Rise Time of Both SCLOCK and SDATA		300	ns	26
t <sub>F</sub>	Fall Time of Both SCLOCK and SDATA		300	ns	26
$t_{SUP}^{-1}$	Pulsewidth of Spike Suppressed		50	ns	26

NOTE

<sup>1</sup>Input filtering on both the SCLOCK and SDATA inputs suppress noise spikes which are less than 50 ns.

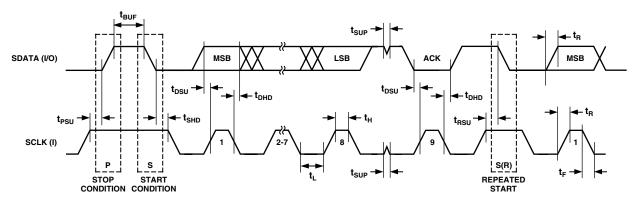


Figure 26. l<sup>2</sup>C-Compatible Interface Timing

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Paramete	r	Min	Typ	Max	Units	Figure
SPI MAS	SPI MASTER MODE TIMING (CPHA = 1)					
$t_{SL}$	SCLOCK Low Pulsewidth		330		ns	27
$t_{SH}$	SCLOCK High Pulsewidth		330		ns	27
$t_{\mathrm{DAV}}$	Data Output Valid After SCLOCK Edge			50	ns	27
$t_{DSU}$	Data Input Setup Time Before SCLOCK Edge	100			ns	27
$t_{ m DHD}$	Data Input Hold Time After SCLOCK Edge	100			ns	27
$t_{\mathrm{DF}}$	Data Output Fall Time		10	25	ns	27
$t_{DR}$	Data Output Rise Time		10	25	ns	27
$t_{SR}$	SCLOCK Rise Time		10	25	ns	27
$t_{SF}$	SCLOCK Fall Time		10	25	ns	27

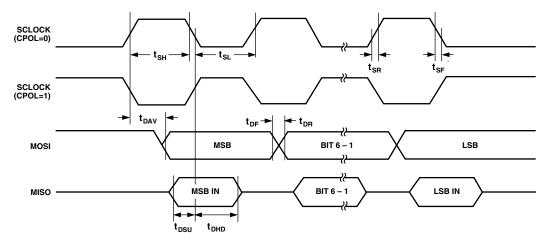


Figure 27. SPI Master Mode Timing (CPHA = 1)

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Parameter	•	Min	Тур	Max	Units	Figure
SPI MASTER MODE TIMING (CPHA = 0)						
$t_{SL}$	SCLOCK Low Pulsewidth		330		ns	28
$t_{SH}$	SCLOCK High Pulsewidth		330		ns	28
$t_{DAV}$	Data Output Valid After SCLOCK Edge			50	ns	28
$t_{DOSU}$	Data Output Setup Before SCLOCK Edge			150	ns	28
$t_{DSU}$	Data Input Setup Time Before SCLOCK Edge	100			ns	28
$t_{ m DHD}$	Data Input Hold Time After SCLOCK Edge	100			ns	28
$t_{\mathrm{DF}}$	Data Output Fall Time		10	25	ns	28
$t_{DR}$	Data Output Rise Time		10	25	ns	28
t <sub>SR</sub>	SCLOCK Rise Time		10	25	ns	28
$t_{SF}$	SCLOCK Fall Time		10	25	ns	28

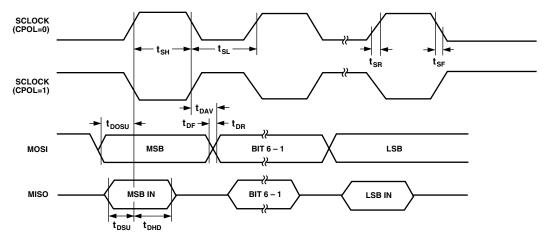


Figure 28. SPI Master Mode Timing (CPHA = 0)

Parameter		Min	Typ	Max	Units	Figure
SPI SLAVE MODE TIMING (CPHA = 1)						
t <sub>SS</sub>	SS to SCLOCK Edge	0			ns	29
$t_{SL}$	SCLOCK Low Pulsewidth		330		ns	29
$t_{SH}$	SCLOCK High Pulsewidth		330		ns	29
$t_{DAV}$	Data Output Valid After SCLOCK Edge			50	ns	29
$t_{DSU}$	Data Input Setup Time Before SCLOCK Edge	100			ns	29
$t_{ m DHD}$	Data Input Hold Time After SCLOCK Edge	100			ns	29
$t_{DF}$	Data Output Fall Time		10	25	ns	29
$t_{DR}$	Data Output Rise Time		10	25	ns	29
$t_{SR}$	SCLOCK Rise Time		10	25	ns	29
$t_{SF}$	SCLOCK Fall Time		10	25	ns	29
$t_{SFS}$	SS High After SCLOCK Edge	0			ns	29

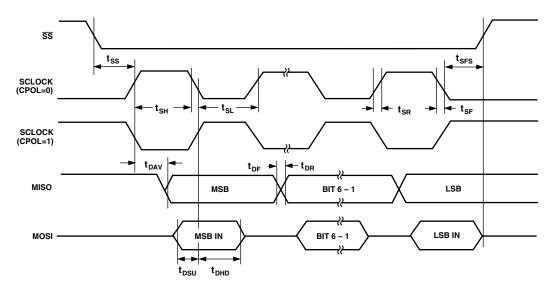


Figure 29. SPI Slave Mode Timing (CPHA = 1)

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Parameter		Min	Typ	Max	Units	Figure	
SPI SLAVE MODE TIMING (CPHA = 0)							
$t_{SS}$	SS to SCLOCK Edge	0			ns	30	
$t_{SL}$	SCLOCK Low Pulsewidth		330		ns	30	
$t_{SH}$	SCLOCK High Pulsewidth		330		ns	30	
$t_{DAV}$	Data Output Valid After SCLOCK Edge			50	ns	30	
$t_{DSU}$	Data Input Setup Time Before SCLOCK Edge	100			ns	30	
$t_{ m DHD}$	Data Input Hold Time After SCLOCK Edge	100			ns	30	
$t_{\mathrm{DF}}$	Data Output Fall Time		10	25	ns	30	
$t_{DR}$	Data Output Rise Time		10	25	ns	30	
$t_{SR}$	SCLOCK Rise Time		10	25	ns	30	
$t_{SF}$	SCLOCK Fall Time		10	25	ns	30	
$t_{DOSS}$	Data Output Valid After SS Edge			20	ns	30	
$t_{SFS}$	SS High After SCLOCK Edge				ns	30	

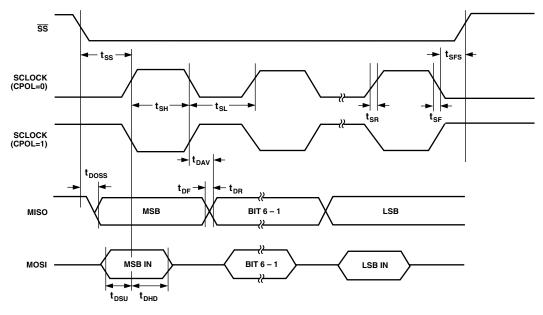
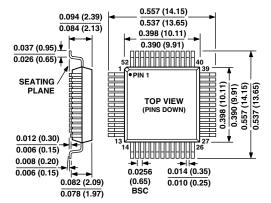


Figure 30. SPI Slave Mode Timing (CPHA = 0)

#### **OUTLINE DIMENSIONS**

Dimensions shown in inches and (mm).

## 52-Lead Plastic Quad Flatpack (S-52)



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